

L Number	Hits	Search Text	DB	Time stamp
-	1148	716/19	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 11:48
-	758	716/21	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 11:48
-	11	(716/19).ccls. and (mask or reticle) and (CAD same ((electron adj beam) or EB) same data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 16:46
-	15	(716/21).ccls. and (mask or reticle) and (CAD same ((electron adj beam) or EB) same data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 13:30
-	1	(716/21).ccls. and (mask or reticle) and (CAD same ((electron adj beam) or EB) same data) and (inspect\$ adj data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 13:33
-	2	(716/\$).ccls. and (mask or reticle) and (CAD same ((electron adj beam) or EB) same data) and (inspect\$ adj data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 13:34
-	13	(mask or reticle) and (CAD same ((electron adj beam) or EB) same data) and (inspect\$ adj data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 13:35
-	2	(mask or reticle) and (CAD same ((electron adj beam) or EB) same data) and ((data adj conversion) adj error)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 17:11
-	2	(mask or reticle) and (((electron adj beam) or EB) same data) and ((data adj conversion) adj error)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 17:13
-	3	(mask or reticle) and ((data adj conversion) adj error)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 17:20
-	3	(mask or reticle) and ((data adj (translation or conversion) adj error))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 18:26
-	2	(mask or reticle) and CAD and ((data adj (translation or conversion) adj error))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 18:27

	2	(mask or reticle) and CAD and ((data adj (translation or conversion) adj (error or mistake)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 18:29
	2	CAD and ((data adj (translation or conversion) adj (error or mistake)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 18:30
	0	(beam adj lithograph) same (inspection adj method)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 10:49
	0	(beam adj lithograph) and (inspection adj method)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 10:47
	7	(beam adj lithography) same (inspection adj method)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 10:50
	30	(beam adj lithography) and (inspection adj method)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 12:38
	21	(beam adj lithography) and (inspection adj method) and (quality or contrast)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 12:40
	2	(beam adj lithography) and ((inspection adj method) same (quality or contrast))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 12:42
	1	(mask or reticle) and ((data adj verification) same (coordinate adj data))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 13:18
	4	(mask or reticle) and ((data adj verification) same (coordinate))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 13:36
	38	(mask or reticle) and ((data adj (check\$ or verification)) same (coordinate))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 13:52
	9	(mask or reticle) and (electron adj beam) and ((data adj (check\$ or verification)) same (coordinate))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 14:02

	1	(mask or reticle) and (electron adj beam) and ((data adj (check\$ or verification)) same ((two adj dimension\$) adj (coordinate)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 14:29
	0	(mask or reticle) and (electron adj beam) and ((pattern adj (check\$ or verification)) same ((two adj dimension\$) adj (coordinate)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 14:30
	1	(mask or reticle) and (electron adj beam) and ((check\$ or verification) same ((two adj dimension\$) adj (coordinate)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 14:34
	64	(mask or reticle) and (electron adj beam) and (pattern adj (check\$ or verification))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 14:34



Membership Publications/Services Standards Conferences Careers/Jobs

Welcome
United States Patent and Trademark OfficeIEEE Xplore®
1 Million Documents
1 Million Users[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)**Quick Links**[» Search Results](#)**Welcome to IEEE Xplore**

- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

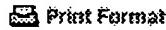
- By Author
- Basic
- Advanced

MEMBERS & SERVICES

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

IEEE ENTERPRISE

- Access the IEEE Enterprise File Cabinet



[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to](#)

Copyright © 2004 IEEE — All rights reserved

9-27-04



Membership Publications/Services Standards Conferences Careers/Jobs

Welcome
United States Patent and Trademark OfficeIEEE Xplore®
1 Million Documents
1 Million Users
RELEASE 1.8[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)**Quick Links**» [Search Results](#)**Welcome to IEEE Xplore®**

- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced

Member Services

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

Enterprise File Cabinet

- Access the IEEE Enterprise File Cabinet

[Print Format](#)

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to](#)

Copyright © 2004 IEEE — All rights reserved

9-27-04

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)

[Membership](#) [Publications/Services](#) [Standards](#) [Conferences](#) [Careers/Jobs](#)



Welcome
United States Patent and Trademark Office



IEEE Xplore®
1 Million Documents
1 Million Users

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)

Quick Links

[» Search Results](#)

Welcome to IEEE Xplore®

- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced

MEMBERSHIP SERVICES

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

IEEE ENTERPRISE

- Access the IEEE Enterprise File Cabinet

Print Format

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to](#)

Copyright © 2004 IEEE — All rights reserved

9-27-04